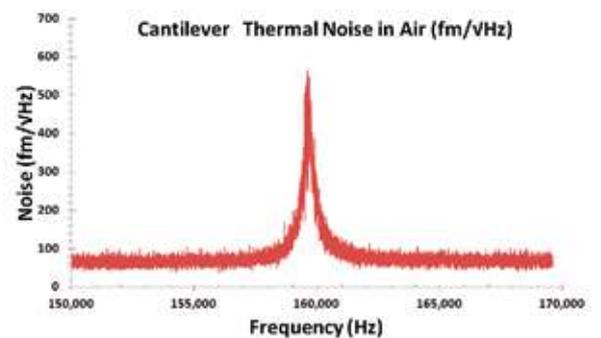


ezAFM™

Atomic Force Microscope

for Research, Education and QC Applications

- Innovative technology with superior performance
- Setup under an hour





Technical Specifications

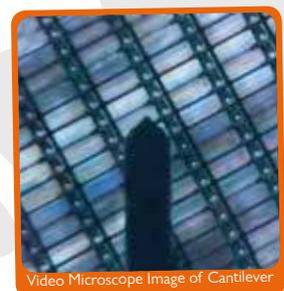
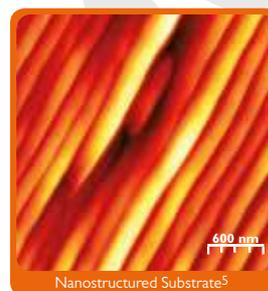
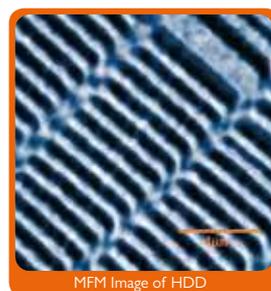
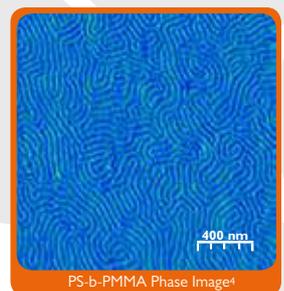
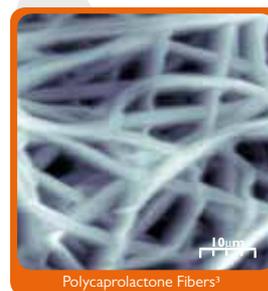
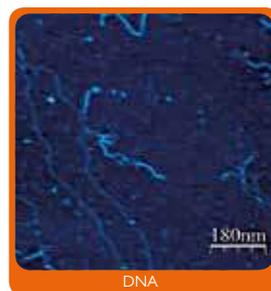
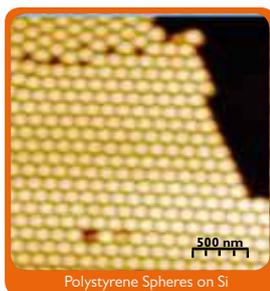
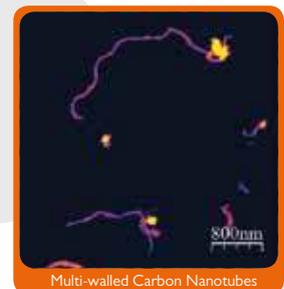
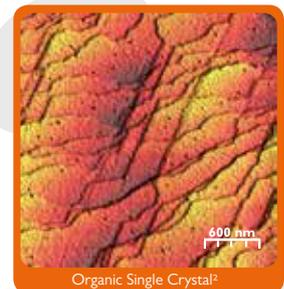
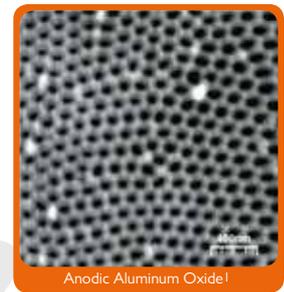
- Alignment free cantilevers, commercially available
- 120x120x40 μm or 40x40x4 μm scan range
- Contact, Dynamic/Phase Imaging, Lateral Force & MFM modes
- 65 fmV/Hz noise floor
- 2 μm resolution integrated optical microscope
- Full HD, 390x230 μm FOV, 2,516x1,960 pixels, 30fps, video camera
- 24Bit ADCs/DACs
- Digital Feedback with FPGA/DSP
- Free software upgrades for lifetime
- Unlimited user license
- USB interfaces
- Sample Size, 10x10x5mm (Configurable for unlimited sample size)

Extended Imaging Options

- Scratching Lithography
- Scanning Tunneling Microscopy (ezSTM)
- Liquid Cell

Accessories

- Signal Access Module
- 40 mm stroke XY motorized sample positioner
- 2 mm stroke XY manual sample positioner



(1) Sample courtesy of Dr. Fatih Buyukserin, TOBB University (2) Sample courtesy of Dr. Yasuo Nakayama, Chiba University (3) Sample courtesy of Dr. Aylin Sendemir, Ege University (4) Sample courtesy of Dr. Serdar Onses, Erciyes University (5) Sample courtesy of Dr. Francesco Buatier, Genova University